Bottom View



P-Channel Enhancement Mode MOSFET

Top View

SOT23-3L

Features

- -30V / -3.5A
- $R_{DS(ON)}$ =40mΩ (typ) @VGS=10V $R_{DS(ON)}$ =60mΩ (typ) @VGS=4.5V
- 100% UIS & RG Tested
- Reliableand Rugged
- Lead Freeand Green Devices Available (RoHS Compliant)

Applications

 Power Management for Industrial DC/DC Converters

G S P Channel

Marking

Marking	A3****
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Absolute Maximum Ratings (T_A= 25°C unless otherwise noted)

Symbol	Parameter		Rating	Unit		
Common Ratings						
V _{DSS}	Drain-Source Voltage		-30	V		
V_{GSS}	Gate-Source Voltage	±12	V			
I _D	Continuous Drain Current	T _J =150°C	-3.5			
I _{DM}	Pulsed Drain Current	-18	A			
I _S	Diode Continuous Forward Current		-1.5	А		
T_{STG}, T_{j}	Storage Temperature Range		-55 to 150	°C		
PD	Power Dissipation	T _A =25°C	1.4	W		
		T _A =70°C	0.9	VV		
$R_{ heta JA}$	Thermal Resistance-Junction to Ambient		120	°C/W		

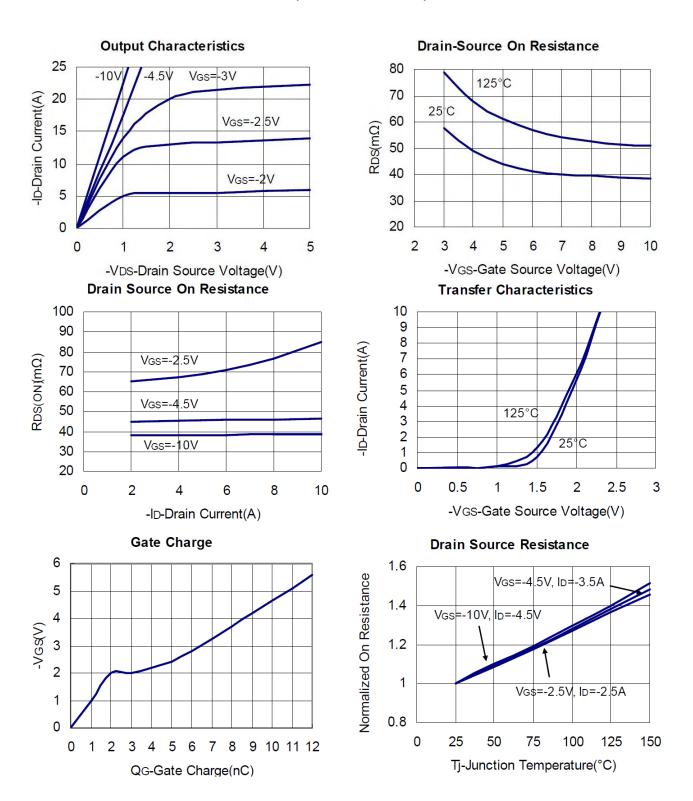


Electrical Characteristics $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Static Char	acteristics	-		<u></u>	<u>.</u>	I
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =-250μA	-30	-	-	V
	Zero Gate Voltage Drain Current	V _{DS} =-24V, V _{GS} =0V	-	-	-1	Δ.
I _{DSS}		T _j =55°C			-10	μΑ
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = -250 \mu A$	-0.6	-	-1.4	V
I _{GSS}	Gate Leakage Current	V _{GS} =±12V, V _{DS} =0V	-	-	±100	nA
	Drain-Source On-state Resistance	V _{GS} =-10V, I _{DS} =-3.5A	-	55	70	mΩ
R _{DS(ON)}		V _{GS} =-4.5V, I _{DS} =-3A	-	65	80	
		V _{GS} =-2.5V, I _{DS} =-2.5A		85	95	
Body Diode	e Characteristics			•	•	
V _{SD}	Diode Forward Voltage	I _{SD} =-1A, V _{GS} =0V	-	-0.7	-1.0	V
Dynamic C	haracteristics			•	•	
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-15V, Frequency=1.0MHz	-	245	-	pF
C _{oss}	Output Capacitance		-	57	-	
C _{rss}	Reverse transfer capacitance		-	32	-	
t _{d(ON)}	Turn-on delay Time		-	8	15	
t _r	Turn-on rise Time	V_{GS} =-10V , V_{DS} =-15V R_{G} =6 Ω , I_{D} =1A, R_{L} =15 Ω ,	-	2	5	nS
t _{d(OFF)}	Turn-off delay Time		-	31	40	
t _f	Turn-off rise Time		-	6	6	
Gate Charg	e Characteristics			•	-	-
Q_g	Total Gate Charge		-	6	-	nC
Q_{gs}	Gate-Source Charge	V_{DS} =-15V, V_{GS} =-10V, I_{DS} =-3.5A	-	1.2	-	
Q_{gd}	Gate-Drain Charge	53	-	1.5	-	

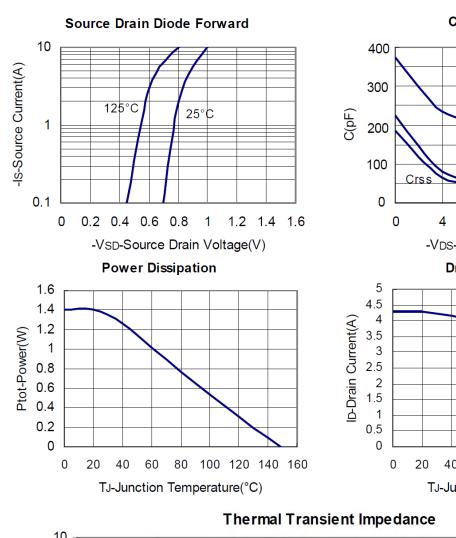


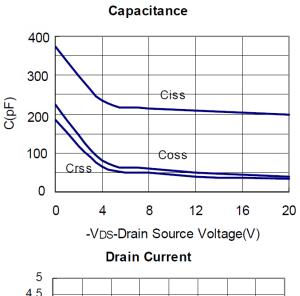
TYPICAL CHARACTERISTICS (25 °C Unless Note)

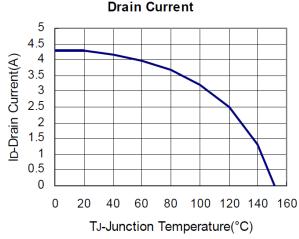


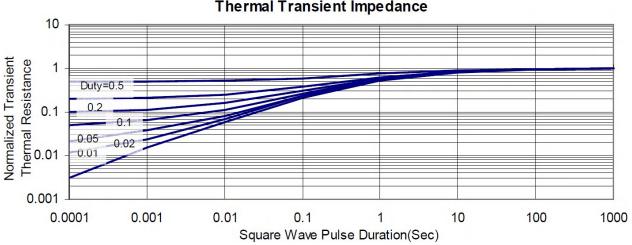


TYPICAL CHARACTERISTICS (continuous)



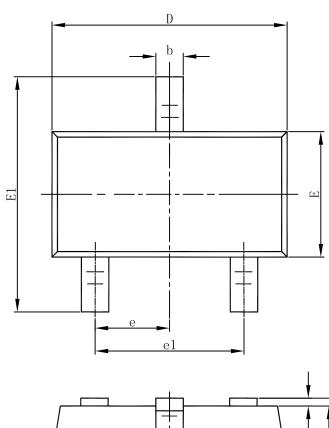


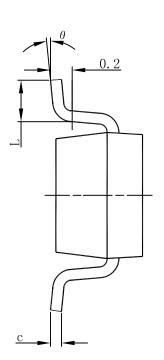


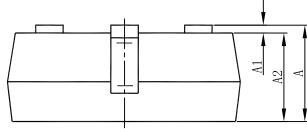




SOT23-3L PACKAGE OUTLINE DIMENSIONS







Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
Α	1.050	1.250	0.041	0.049	
A1	0.000	0.100	0.000	0.004	
A2	1.050	1.150	0.041	0.045	
b	0.300	0.500	0.012	0.020	
С	0.100	0.200	0.004	0.008	
D	2.820	3.020	0.111	0.119	
E	1.500	1.700	0.059	0.067	
E1	2.650	2.950	0.104	0.116	
е	0.950	(BSC)	0.037(BSC)		
e1	1.800	2.000	0.071	0.079	
L	0.300	0.600	0.012	0.024	
θ	0°	8°	0°	8°	



Attention

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